

ACS157MS

Radiation Hardened Quad 2-Input Non-Inverting Multiplexer

December 1997

Features

- QML Qualified Per MIL-PRF-38535 Requirements
- 1.25Micron Radiation Hardened SOS CMOS
- Radiation Environment
 - Latch-up Free Under any Conditions

 - SEU LET Threshold>100MeV/(mg/cm²)
- Input Logic Levels . . . V_{IL} = (0.3)(Vcc), V_{IH} = (0.7)(Vcc)
- Output Current ±12mA
- Propagation Delay14ns

Applications

- 4-Bit Source Selection
- Data Routing
- High Frequency Switching

Description

The Radiation Hardened ACS157MS is a Quad 2-Channel Non-Inverting Multiplexer which selects four bits of data from one of two sources under the control of a single Select pin. The Output Enable input is active LOW and controls all outputs. When \overline{E} is set HIGH, all outputs are forced LOW, regardless of all other input conditions. All inputs are buffered and the outputs are designed for balanced propagation delay and transition times.

The ACS157MS is fabricated on a CMOS Silicon on Sapphire (SOS) process, which provides an immunity to Single Event Latch-up and the capability of highly reliable performance in any radiation environment. These devices offer significant power reduction and faster performance when compared to ALSTTL types.

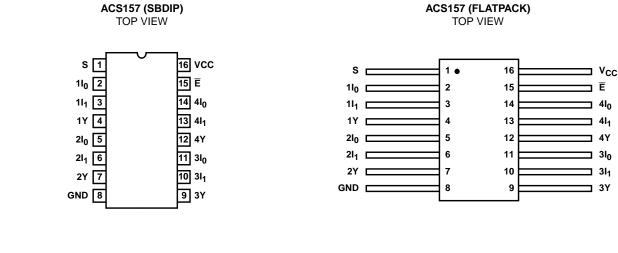
Specifications for Rad Hard QML devices are controlled by the Defense Supply Center in Columbus (DSCC). The SMD numbers listed below must be used when ordering.

Detailed Electrical Specifications for the ACS157 are contained in SMD 5962-98536. A "hot-link" is provided on our homepage with instructions for downloading. http://www.intersil.com/data/sm/index.htm

Ordering Information

SMD PART NUMBER	INTERSIL PART NUMBER	TEMP. RANGE (^O C)	PACKAGE	CASE OUTLINE
5962F9853601VEC	ACS157DMSR-02	-55 to 125	16 Ld SBDIP	CDIP2-T16
N/A	ACS157D/Sample-02	25	16 Ld SBDIP	CDIP2-T16
5962F9853601VXC	ACS157KMSR-02	-55 to 125	16 Ld Flatpack	CDFP4-F16
N/A	ACS157K/Sample-02	25	16 Ld Flatpack	CDFP4-F16
N/A	ACS157HMSR-02	25	Die	N/A

Pinouts



Die Characteristics

DIE DIMENSIONS:

Size: 2390μm x 2390μm (94 mils x 94 mils) Thickness: 525μm ±25μm (20.6 mils ±1 mil) Bond Pad: 110μm x 110μm (4.3 x 4.3 mils)

METALLIZATION: AI

Metal 1 Thickness: $0.7\mu m \pm 0.1\mu m$ Metal 2 Thickness: $1.0\mu m \pm 0.1\mu m$

SUBSTRATE POTENTIAL:

Unbiased Insulator

Metallization Mask Layout

PASSIVATION

Type: Phosphorous Silicon Glass (PSG) Thickness: $1.30\mu m \pm 0.15\mu m$

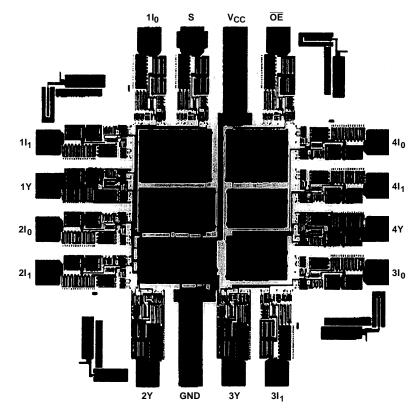
SPECIAL INSTRUCTIONS:

Bond V_{CC} First

ADDITIONAL INFORMATION:

Worst Case Density: $<2.0 \times 10^5 \text{ A/cm}^2$ Transistor Count: 150

ACS157MS



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